

1. Record Nr.	UNINA9911101657603321
Autore	Aaboe Asger
Titolo	Episodes from the early history of mathematics / / by Asger Aaboe
Pubbl/distr/stampa	Washington, D.C., : Mathematical Association of America, 1998
ISBN	0-88385-928-9
Edizione	[1st ed.]
Descrizione fisica	1 online resource (x, 133 pages) : digital, PDF file(s)
Collana	Anneli Lax New Mathematical Library ; ; 13
Disciplina	510.901
Soggetti	Mathematics - History Mathematics, Ancient
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Title from publisher's bibliographic system (viewed on 02 Oct 2015).
Nota di bibliografia	Includes bibliographical references.
Nota di contenuto	Babylonian mathematics -- Early Greek mathematics and Euclid's construction of the regular pentagon -- Three samples of Archimedean mathematics -- Ptolemy's construction of a trigonometric table.
Sommario/riassunto	Among other things, Aaboe shows us how the Babylonians did calculations, how Euclid proved that there are infinitely many primes, how Ptolemy constructed a trigonometric table in his Almagest, and how Archimedes trisected the angle. Some of the topics may be familiar to the reader, while others will seem surprising or be new.

2. Record Nr.	UNINA9911115501603321
Autore	Mishra Nileshta
Titolo	Influence of strain on the functionality of ink-jet printed thin films and devices on flexible substrates
Pubbl/distr/stampa	KIT Scientific Publishing, 2019
ISBN	1000086125
Descrizione fisica	1 online resource (X, 127 p. p.)
Collana	Schriftenreihe des Instituts für Angewandte Materialien, Karlsruher Institut für Technologie
Soggetti	Technology: general issues
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Sommario/riassunto	Ink-jet printed devices on the flexible substrate are inexpensive and large area compatible as compared to rigid substrates. However, during fabrication and service they are subjected to complex strains, resulting in crack formation or delamination within the layers, affecting the device performance. Therefore, it is necessary to understand their failure mechanisms by correlating their electrical or structural properties with applied strain, supported by detailed microstructural investigations.